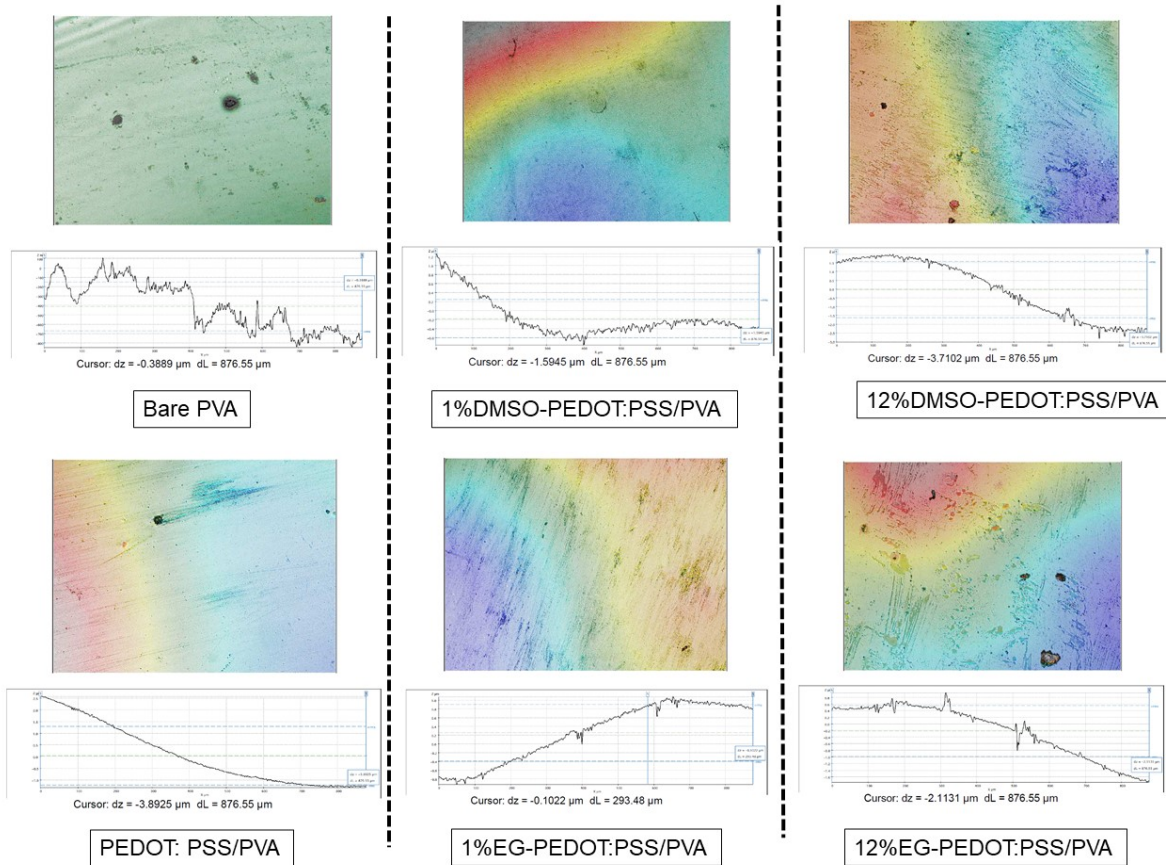
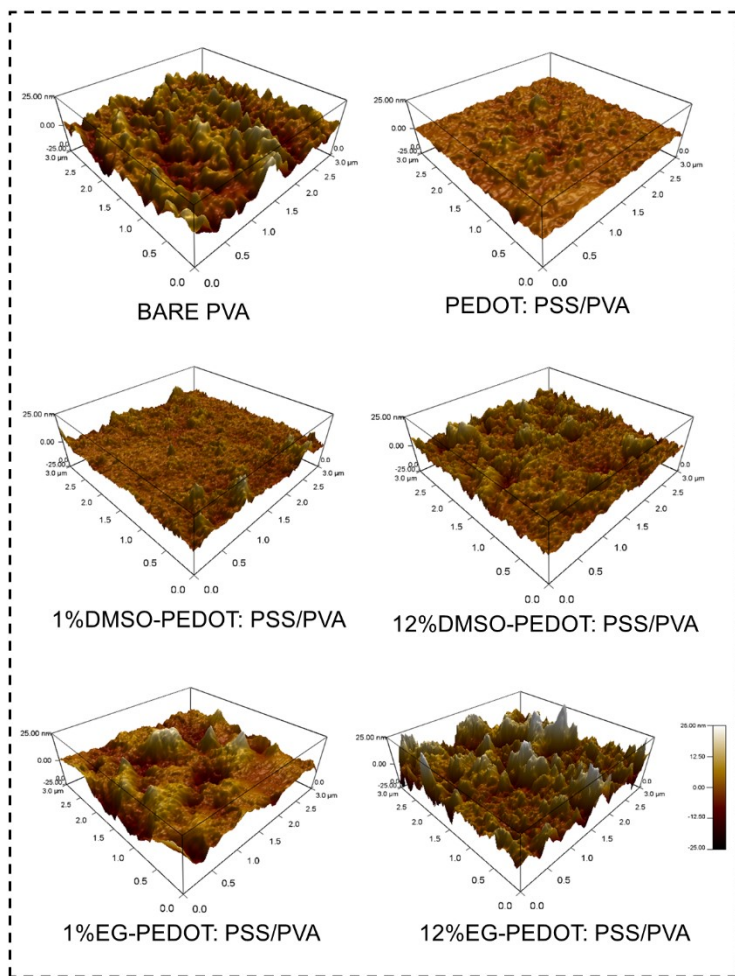
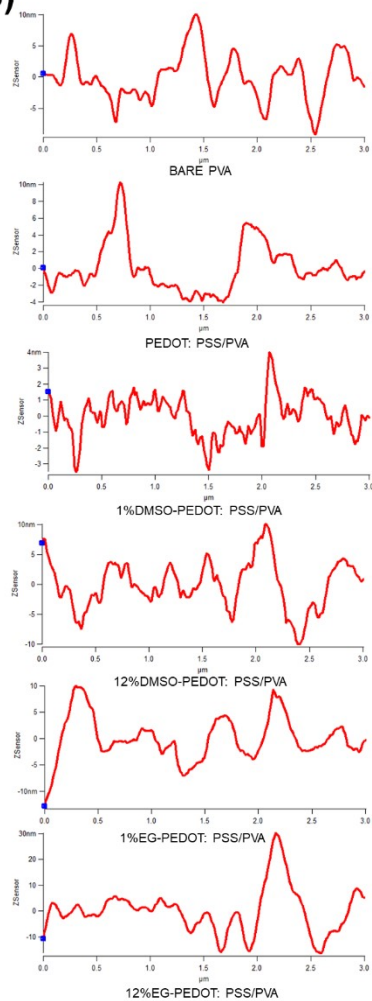


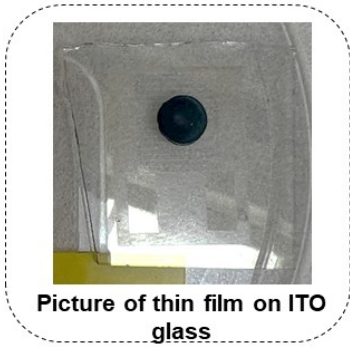
SUPPLEMENTARY



S1 The topography of fabricated thin films (in contour mode) and its surface roughness distribution captured from profilometry analysis.

(a)**(b)**

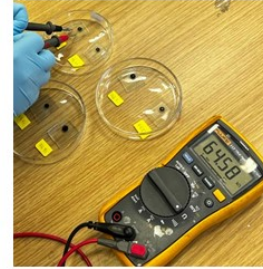
S2 (a) AFM 3D images of selected fabricated thin films and (b) The surface roughness distribution of thin films graph from Z-sensor retrace mode.



Picture of thin film on ITO glass



BARE PVA



PEDOT: PSS/PVA



1% DMSO-PEDOT: PSS/PVA



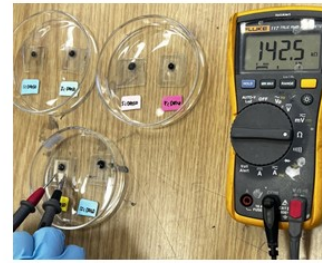
3% DMSO-PEDOT: PSS/PVA



5% DMSO-PEDOT: PSS/PVA



7% DMSO-PEDOT: PSS/PVA



9% DMSO-PEDOT: PSS/PVA



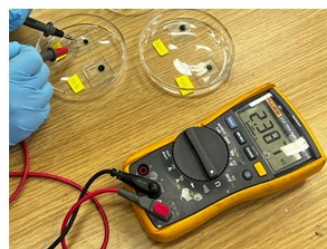
1% EG-PEDOT: PSS/PVA



3% EG-PEDOT: PSS/PVA



5% EG-PEDOT: PSS/PVA

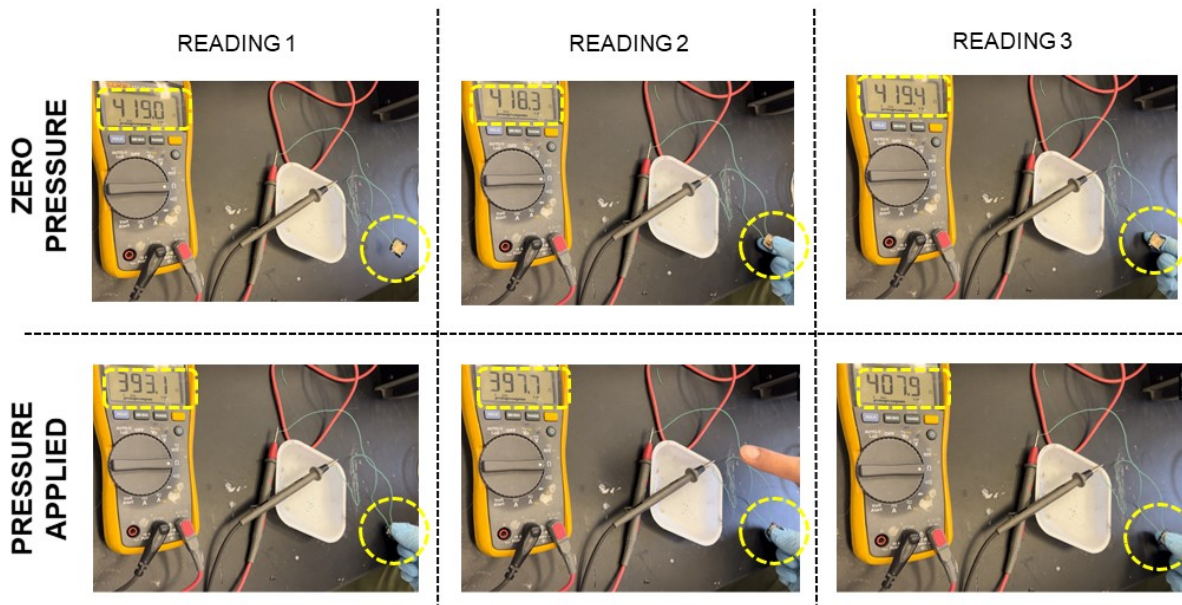


7% EG-PEDOT: PSS/PVA

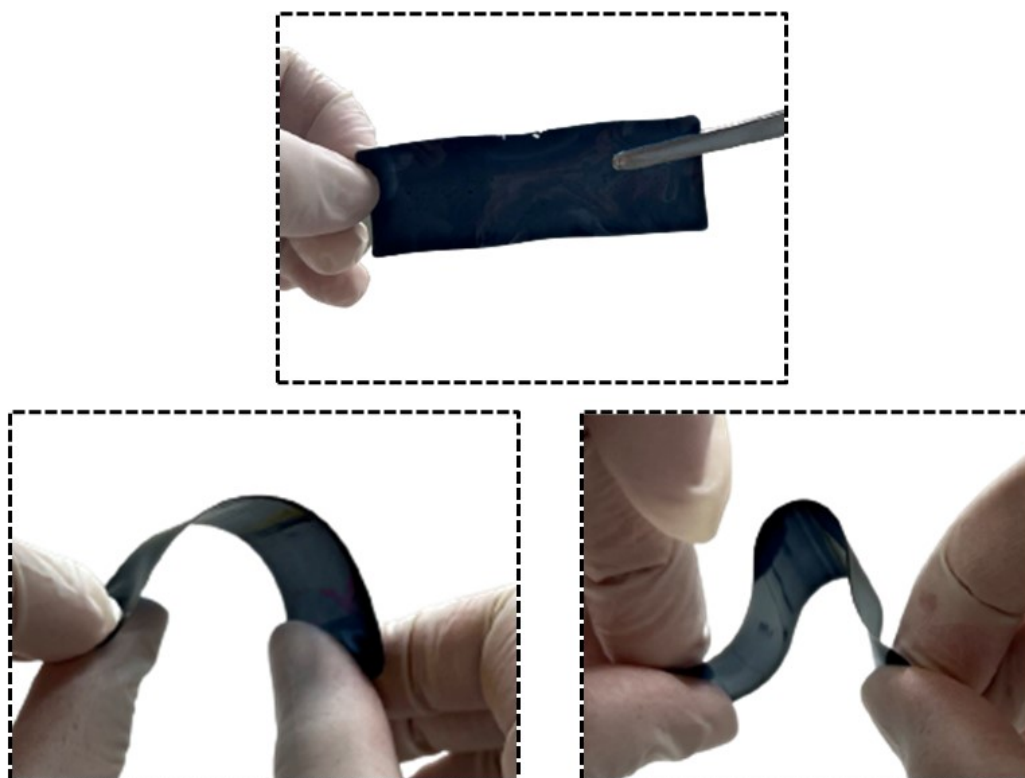


9% EG-PEDOT: PSS/PVA

S3 The resistivity measurement of all PEDOT: PSS/PVA thin films coated on interdigital electrode (ITO glass) by using multi-meter.



S4 The changes in resistivity reading from multimeter on thin film sensor when pressure is applied, hypothesizing the ability of films to be applied as pressure sensors.



S5 The pictures of fabricated PEDOT: PSS/PVA thin films applied as strain sensors.